# SGM7222

# High Speed USB 2.0 (480Mbps) DPDT Analog Switch

### **GENERAL DESCRIPTION**

The SGM7222 is a high-speed, low-power double-pole/ double-throw (DPDT) analog switch that operates from a single +1.8V to +4.3V power supply.

SGM7222 is designed for the switching of high-speed USB 2.0 signals in handset and consumer applications, such as cell phones, digital cameras, and notebooks with hubs or controllers with limited USB I/Os.

The SGM7222 has low bit-to-bit skew and high channel-to-channel noise isolation, and is compatible with various standards, such as high-speed USB 2.0 (480 Mbps). Each switch is bidirectional and offers little or no attenuation of the high-speed signals at the outputs. Its bandwidth is wide enough to pass high-speed USB 2.0 differential signals (480 Mb/s) with good signal integrity.

The SGM7222 contains special circuitry on the D+/Dpins which allows the device to withstand a  $V_{BUS}$  short to D+ or D- when the USB devices are either powered off or powered on.

SGM7222 is available in Pb-free WQFN-10 and MSOP-10 packages. It operates over an ambient temperature range of  $-40^{\circ}$ C to  $+85^{\circ}$ C.

## **APPLICATIONS**

Route Signals for USB 2.0 MP3 and Other Personal Media Players Digital Cameras and Camcorders Portable Instrumentation Set-Top Box PDAs

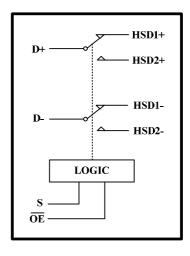


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### FEATURES

- Ron is Typically  $4.5\Omega$  at +3.0V
- Low Bit-to-Bit Skew: 50ps (TYP)
- Voltage Operation : +1.8V to +4.3V
- Fast Switching Times: ton 10ns toff 22ns
- Low Crosstalk: -41dB at 250MHz
- Power-Off Protection when V<sub>+</sub> = 0V,
  D+/D- Pins can Tolerate up to 5.25V
- High Off-Isolation: -35dB at 250MHz
- Rail-to-Rail Input and Output Operation
- Break-Before-Make Switching
- Extended Industrial Temperature Range: -40℃ to +85℃
- Lead (Pb) Free WQFN-10 and MSOP-10 Packages

#### **BLOCK DIAGRAM**



### **ORDERING INFORMATION**

MODEL	PIN- PACKAGE	SPECIFIED TEMPERATURE RANGE	ORDERING NUMBER	PACKAGE MARKING	PACKAGE OPTION
SC 147222	MSOP-10	-40℃ to +85℃	SGM7222YMS10/TR	SGM7222YMS10	Tape and Reel, 3000
SGM7222	WQFN-10	-40℃ to +85℃	SGM7222YWQ10/TR	7222	Tape and Reel, 3000

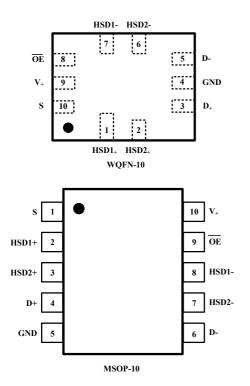
### **ABSOLUTE MAXIMUM RATINGS**

V+, IN to GND	0V to +4.6V
Analog, Digital voltage range	0.3V to (V++0.3V)
Continuous Current HSDn or Dn	±100mA
Peak Current HSDn or Dn	±150mA
Operating Temperature Range	40℃ to +85℃
Junction Temperature	+150℃

Storage Temperature	65℃ to +150℃
Lead Temperature (soldering, 10s)	+260℃
ESD Susceptibility	
НВМ	4000V
MM	400V

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

# PIN CONFIGURATIONS (TOP VIEW) PIN DESCRIPTION



PI	N	NAME	FUNCTION		
WQFN-10	MSOP-10	INAME	FUNCTION		
9	10	V+	Power Supply		
4	5	GND	Ground		
10	1	S	Select Input		
8	9	ŌĒ	Output Enable		
1,2,	2,3,	HSD1+, HSD2+,			
7,6,	8,7,	HSD1-, HSD2-,	Data Ports		
3,5	4,6	D+, D-			

# **FUNCTION TABLE**

ŌĒ	S	HSD1+ HSD1-	HSD2+ HSD2-
0	0	ON	OFF
0	1	OFF	ON
1	×	OFF	OFF

Switches Shown For Logic "0" Input

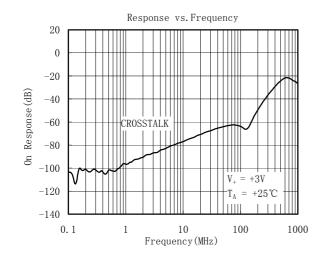


# **ELECTRICAL CHARACTERISTICS**

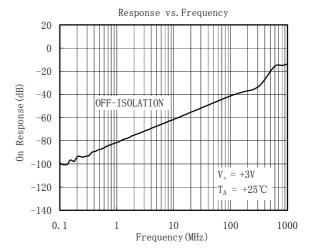
 $(V_{+} = +1.8V \text{ to } +4.3V, \text{ GND} = 0V, V_{IH} = +1.6V, V_{IL} = +0.5V, T_{A} = -40^{\circ}C \text{ to } +85^{\circ}C.$  Typical values are at  $V_{+} = +3.3V$ ,  $T_{A} = +25^{\circ}C$ , unless otherwise noted.)

PARAMETER	SYMBOL	CONDITIONS	TEMP	MIN	TPY	MAX	UNITS	
ANALOG SWITCH			•		•	•		
Analog I/O Voltage (HSD1+, HSD1-, HSD2+, HSD2-)	Vis		-40℃ to +85℃	0		V+	V	
On-Resistance	Ron	$V_{+} = 3.0V, V_{IS} = 0V \text{ to } 0.4V, I_{D} = 8mA,$	+25℃		4.5	8.5	Ω	
OII-Resistance	KON	Test Circuit 1	-40℃ to +85℃			9	\$2	
On-Resistance Match Between	$\Delta R_{ON}$	$V_{+} = 3.0V, V_{IS} = 0V \text{ to } 0.4V, I_{D} = 8mA,$	+25℃		0.15	0.6	Ω	
Channels		Test Circuit 1	-40℃ to +85℃			1.6		
On-Resistance Flatness	Rflat(on)	$V_{+} = 3.0V$ , $V_{IS} = 0V$ to 1.0V, $I_{D} = 8mA$ ,	<b>+25℃</b>		1.5	2.0	Ω	
	<b>I U</b> EM(ON)	Test Circuit 1	-40℃ to +85℃			2.6		
Power Off Leakage Current (D+, D-)	Ioff	$V_{+} = 0V, V_{D} = 0V \text{ to } 3.6 \text{ V},$ Vs, $V_{\overline{OE}} = 0V \text{ or } 3.6 \text{ V}$	-40℃ to +85℃			1	μΑ	
Increase in I+ per Control Voltage	Ісст	$V_{+}=3.6V, V_{S} \text{ or } V_{\overline{OE}} = 2.6 V$	-40℃ to +85℃			5	μΑ	
Source Off Leakage Current	IHSD2(OFF),IHSD1(OFF)	V+=3.6V, VIS = 3.3V/ 0.3V, VD= 0.3V/ 3.3V	-40℃ to +85℃			1	μΑ	
Channel On Leakage Current	IHSD2(ON), IHSD1(ON)	V+=3.6V, V15 = 3.3V/ 0.3V, VD= 3.3V/ 0.3V or floating	-40℃ to +85℃			1	μΑ	
DIGITAL INPUTS								
Input High Voltage	Vih		-40℃ to +85℃	1.6			V	
Input Low Voltage	Vil		-40℃ to +85℃			0.5	V	
Input Leakage Current	IIN	$V_{+} = 3.0V$ , $V_{s}$ , $V_{\overline{oE}} = 0V$ or $V_{+}$	-40℃ to +85℃			1	μΑ	
DYNAMIC CHARACTERISTI	CS							
Turn-On Time	ton	$V_{IS} = 0.8V, R_L = 50\Omega, C_L = 10pF,$	<b>+25</b> ℃		10		ns	
Turn-Off Time	toff	Test Circuit 2	<b>+</b> 25℃		22		ns	
Break-Before-Make Time Delay	t⊳	$V_{IS} = 0.8V, R_L = 50\Omega, C_L = 10pF,$ Test Circuit 3	+25℃		4		ns	
Propagation Delay	tpd	$R_L = 50\Omega$ , $C_L = 10 pF$	+25℃		0.3		ns	
Off Isolation	Oiso	Signal = 0dBm, $R_L$ = 50 $\Omega$ , f = 250MHz, Test Circuit 4	+25℃		-35		dB	
Channel-to-Channel Crosstalk	Xtalk	Signal = 0dBm, $R_L$ = 50 $\Omega$ , f = 250MHz, Test Circuit 5	<b>+25</b> ℃		-41		dB	
–3dB Bandwidth	BW	Signal = 0dBm, $R_L$ = 50 $\Omega$ , $C_L$ = 5pF Test Circuit 6	+25℃		550		MHz	
Channel-to-Channel Skew	tskew	$R_L = 50\Omega, C_L = 10 pF$	+25℃		0.05		ns	
Charge Injection Select Input to Common I/O	Q	$V_G = GND, C_L = 1.0nF, R_G = 0\Omega,$ $Q = C_L \times V_{OUT}, Test Circuit 7$	+25℃		11		pC	
HSD+, HSD-, D+, D- ON Capacitance	Con		+25℃		6.5		pF	
POWER REQUIREMENTS								
Power Supply Range	V+		-40℃ to +85℃	1.8		4.3	V	
Power Supply Current	I+	$V_{+} = 3.0V, V_{S}, V_{\overline{OE}} = 0V \text{ or } V_{+}$	-40℃ to +85℃			1	μΑ	

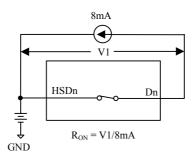
Specifications subject to changes without notice.



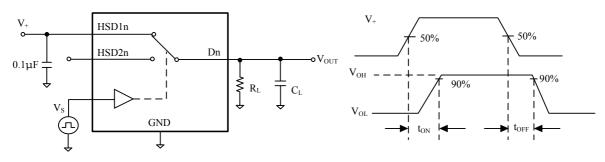
# **TYPICAL PERFORMANCE CHARACTERISTICS**



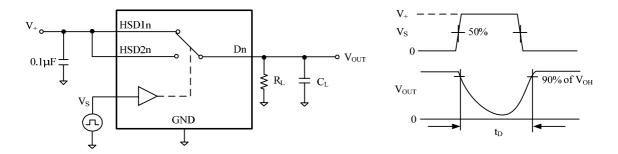
# **TEST CIRCUITS**



Test Circuit 1. On Resistance

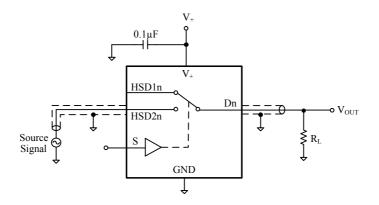


Test Circuit 2. Switching Times (ton, toff)

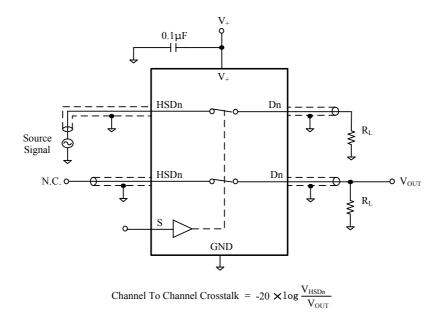


Test Circuit 3. Break-Before-Make Time (tD)

# **TEST CIRCUITS (Cont.)**

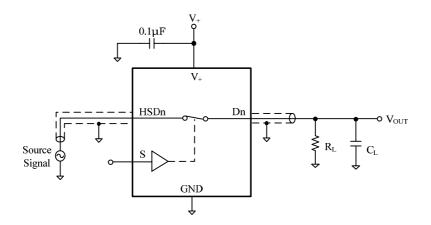


Test Circuit 4. Off Isolation

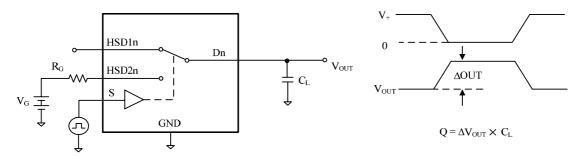


Test Circuit 5. Channel-to-Channel Crosstalk

# **TEST CIRCUITS (Cont.)**



Test Circuit 6. -3dB Bandwidth





# **APPLICATION NOTES:**

### Meeting USB 2.0 V<sub>BUS</sub> Short Requirements

In section 7.1.1 of the USB 2.0 specification, it notes that USB devices must be able to withstand a  $V_{BUS}$  short to D+ or D- when the USB devices is either powered off or powered on. The SGM7222 can be successfully configured to meet both these requirements.

#### **Power-Off Protection**

For a V<sub>BUS</sub> short circuit, the switch is expected to withstand such a condition for at least 24 hours. The SGM7222 has specially designed circuitry which prevents unintended signal bleed through as well as guaranteed system reliability during a power-down, over-voltage condition. The protection has been added to the common pins (D+, D-).

#### **Power-On Protection**

The USB 2.0 specification also notes that the USB device should be capable of withstanding a V<sub>BUS</sub> short during transmission of data. This modification works by limiting current flow back into the V+ rail during the over-voltage event so current remains within the safe operating range. In this application, the switch passes the full 5.25V input signal through to the selected output, while maintaining specified off isolation on the un-selected pins.

### SGM7222 USB2.0 Signal Quality Compliance Tests

Figures 1 and 2 show the test results for USB eye diagram tests. A summary of the USB tests is provided in Table 1. The SGM7222 passes the high speed signal quality, eye diagram and jitter tests.

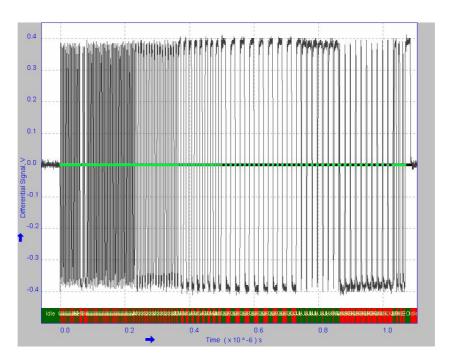


Figure 1. Waveform Plot

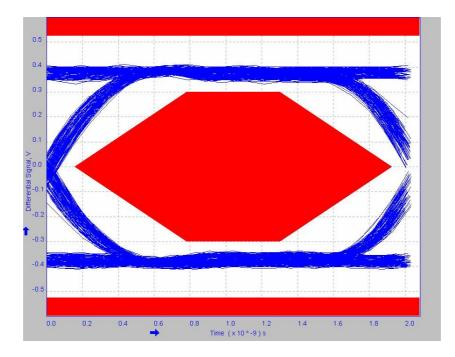


Figure 2. High Speed Signal Quality Eye Diagram Test (V+ = 3.3V)

### SGM7222 USB2.0 Signal Quality Compliance Tests (Cont.)

Measurement Name	MIN	MAX	Mean	pk-pk	Standard Deviation	RMS	Population	Status
Eye Diagram Test	-	-	-	-	-	-	-	Pass
Signal Rate	469.9358 Mbps	493.4413 Mbps	479.9700 Mbps	0.0000 bps	5.586580 Mbps	480.4200 Mbps	512	Pass
EOP Width	-	-	16.58804ns	-	-	-	1	Pass
EOP Width (Bits)	-	-	7.961762	-	-	-	1	Pass
Falling Edge Rate	1.064231 kV/μs	1.228955 kV/μs	1.143136 kV/μs	164.7235 V/μs	35.43800 V/μs	1.143680 kV/μs	107	Pass
Rising Edge Rate	1.063269 kV/μs	1.227966 kV/μs	1.136558 kV/μs	164.6970 V/μs	31.49494 V/μs	1.136990 kV/μs	108	Pass

Table 1. Summary of the USB 2.0 Signal Quality Tests Results

Additional Information:

Consecutive Jitter range: -82.97ps to 72.87ps RMS Jitter 35.08ps

KJ Paired Jitter range: -25.05ps to 23.05ps RMS Jitter 9.259ps

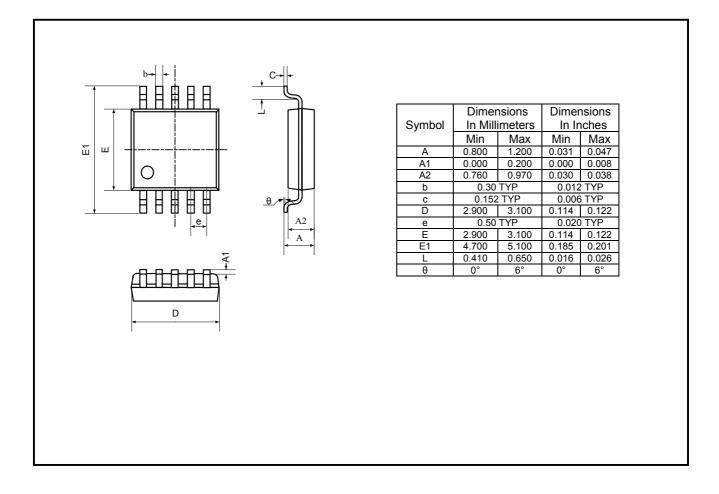
JK Paired Jitter range: -20.96ps to 30.12ps RMS Jitter 9.734ps

• Rising Edge Rate: 1.136558kV/µs (Equivalent Rise Time = 563.10ps)

• Falling Edge Rate: 1.143136kV/µs (Equivalent Fall Time = 559.86ps)

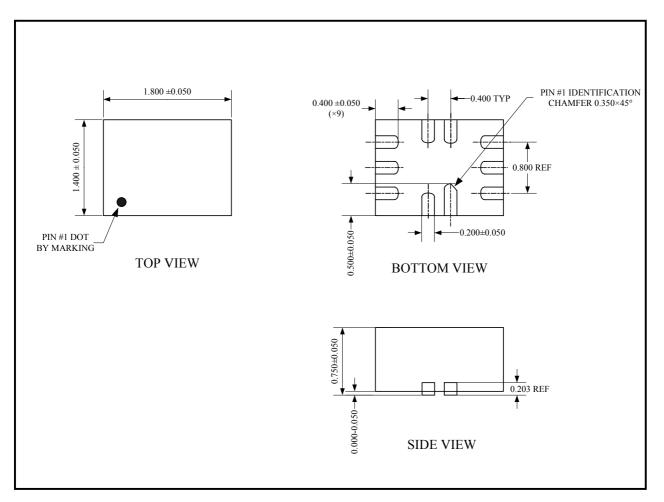
# PACKAGE OUTLINE DIMENSIONS

### MSOP-10



# PACKAGE OUTLINE DIMENSIONS

### WQFN-10



Note: All linear dimensions are in millimeters.

## **REVISION HISTORY**

Location

04/2008- Data Sheet REV. A



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